MQX2 Hipot in Helium

MQX2

Test Instruments Used

Test Model #	Test Serial #	Calibration Due Date
7550DT	9111100	02/01/2004

Test Date: 08/10/2005

Test Time: 02:42:08 AM

User Name:

Device Tested

Model Number: BoX C LQX2

Serial Number: A1 thru A5

Setup Filename: IN HELIUM

Results

	Test Type	Memory	Step	Pass/Fail	Test Result	Timer	Parameter 1	Parameter 2
1	DC Withstand	10	1	Pass	Pass	60.0s	5.00KV	0.0microamps

MQ X2

Test Instruments Used

Test Model #	Test Serial #	Calibration Due Date
7550DT	9111100	02/01/2004

Test Date: 08/10/2005

Test Time: 02:45:35 AM

User Name:

Device Tested

Model Number: BoX C LQX2

Serial Number: A6 thru B4

Setup Filename: 1N Helium

Results

	Test Type	Memory	Step	Pass/Fail	Test Result	Timer	Parameter 1	Parameter 2
1	DC Withstand	10	1	Pass	Pass	60.0s	5.00KV	0.0microamps

MQX2

Test Instruments Used

Test Model #	Test Serial #	Calibration Due Date
7550DT	9111100	02/01/2004

Test Date: 08/10/2005

Test Time: 02:48:31 AM

User Name:

Device Tested

Model Number: BoX C LQX2

Serial Number: B5 thru C3

Setup Filename: IN Helium

Results

	Test Type	Memory	Step	Pass/Fail	Test Result	Timer	Parameter 1	Parameter 2
1	DC Withstand	10	1	Pass	Pass	60.0s	5.00KV	0.0microamps

MQX2

Test Instruments Used

Test Model #	Test Serial #	Calibration Due Date
7550DT	9111100	02/01/2004

Test Date: 08/10/2005

Test Time: 02:51:08 AM

User Name:

Device Tested

Model Number: BoX C LQX2

Serial Number: C4 thru D2

Setup Filename: IN Helium

Results

	Test Type	Memory	Step	Pass/Fail	Test Result	Timer	Parameter 1	Parameter 2
1	DC Withstand	10	1	Pass	Pass	60.0s	5.00KV	0.0microamps

MQX2

Test Instruments Used

Test Model #	Test Serial #	Calibration Due Date
7550DT	9111100	02/01/2004

Test Date: 08/10/2005

Test Time: 02:53:32 AM

User Name:

Device Tested

Model Number: BoX C LQX2

Serial Number: D3 thru D6

Setup Filename: IN HELIUM

Results

	Test Type	Memory	Step	Pass/Fail	Test Result	Timer	Parameter 1	Parameter 2
1	DC Withstand	10	1	Pass	Pass	60.0s	5.00KV	0.0microamps

MQX2

Test Instruments Used

Test Model #	Test Serial #	Calibration Due Date
7550DT	9111100	02/01/2004

Test Date: 08/10/2005

Test Time: 02:55:57 AM

User Name:

Device Tested

Model Number: BoX C LQX2

Serial Number: E1 thru E4

Setup Filename: in Helium

Results

	Test Type	Memory	Step	Pass/Fail	Test Result	Timer	Parameter 1	Parameter 2
1	DC Withstand	10	1	Pass	Pass	60.0s	5.00KV	0.0microamps

MQX2

Test Instruments Used

Test Model #	Test Serial #	Calibration Due Date
7550DT	9111100	02/01/2004

Test Date: 10/26/2005

Test Time: 06:29:42 PM

User Name: Glen Koretky

Device Tested

Model Number: box C MQX2

Serial Number: M9 E5 thru f2

RE TEST FOR MISSING REPORT.

Setup Filename: Leads In Air & He.

Results

	Test Type	Memory	Step	Pass/Fail	Test Result	Timer	Parameter 1	Parameter 2
1	DC Withstand	26	1	Pass	Pass	60.0s	1.40KV	0.0microamps

MQX2

Test Instruments Used

Test Model #	Test Serial #	Calibration Due Date
7550DT	9111100	02/01/2004

Test Date: 08/10/2005

Test Time: 03:00:55 AM

User Name:

Device Tested

Model Number: BoX C LQX2

Serial Number: F3 thruF6

Setup Filename: in Helium

Results

	Test Type	Memory	Step	Pass/Fail	Test Result	Timer	Parameter 1	Parameter 2
1	DC Withstand	10	1	Pass	Pass	60.0s	5.00KV	0.0microamps

MQX2

Test Instruments Used

Test Model #	Test Serial #	Calibration Due Date
7550DT	9111100	02/01/2004

Test Date: 08/10/2005

Test Time: 03:03:28 AM

User Name:

Device Tested

Model Number: BoX C LQX2

Serial Number: G1 thruG3

Setup Filename: IN Helium

Results

	Test Type	Memory	Step	Pass/Fail	Test Result	Timer	Parameter 1	Parameter 2
1	DC Withstand	10	1	Pass	Pass	60.0s	5.00KV	0.0microamps

MQX2

Test Instruments Used

Test Model #	Test Serial #	Calibration Due Date
7550DT	9111100	02/01/2004

Test Date: 08/10/2005

Test Time: 03:05:38 AM

User Name:

Device Tested

Model Number: BoX C LQX2

Serial Number: G4 thruG5

Setup Filename: IN Helium

Results

	Test Type	Memory	Step	Pass/Fail	Test Result	Timer	Parameter 1	Parameter 2
1	DC Withstand	10	1	Pass	Pass	60.0s	5.00KV	0.0microamps

MQX2

Test Instruments Used

Test Model #	Test Serial #	Calibration Due Date
7550DT	9111100	02/01/2004

Test Date: 08/10/2005

Test Time: 03:07:46 AM

User Name:

Device Tested

Model Number: BoX C LQX2

Serial Number: G6 thru H2

Setup Filename: IN Helium

Results

	Test Type	Memory	Step	Pass/Fail	Test Result	Timer	Parameter 1	Parameter 2
1	DC Withstand	10	1	Pass	Pass	60.0s	5.00KV	0.0microamps

MQV2

Test Instruments Used

Test Model #	Test Serial #	Calibration Due Date
7550DT	9111100	02/01/2004

Test Date: 08/10/2005

Test Time: 03:09:55 AM

User Name:

Device Tested

Model Number: BoX C LQX2

Serial Number: H3 thru H4

Setup Filename: IN HELIUM

Results

	Test Type	Memory	Step	Pass/Fail	Test Result	Timer	Parameter 1	Parameter 2
1	DC Withstand	10	1	Pass	Pass	60.0s	5.00KV	0.0microamps

MQX2

Test Instruments Used

Test Model #	Test Serial #	Calibration Due Date
7550DT	9111100	02/01/2004

Test Date: 08/10/2005

Test Time: 03:12:35 AM

User Name:

Device Tested

Model Number: BoX C LQX2

Serial Number: H5 thru I1

Setup Filename: IN HELIUM

Results

	Test Type	Memory	Step	Pass/Fail	Test Result	Timer	Parameter 1	Parameter 2
1	DC Withstand	10	1	Pass	Pass	60.0s	5.00KV	0.0microamps

MBX2

Test Instruments Used

Test Model #	Test Serial #	Calibration Due Date
7550DT	9111100	02/01/2004

Test Date: 08/10/2005

Test Time: 03:14:57 AM

User Name:

Device Tested

Model Number: BoX C LQX2

Serial Number: I2 thru I4

Setup Filename: IN HELIUM

Results

	Test Type	Memory	Step	Pass/Fail	Test Result	Timer	Parameter 1	Parameter 2
1	DC Withstand	10	1	Pass	Pass	60.0s	5.00KV	0.0microamps

MQX2

Test Instruments Used

Test Model #	Test Serial #	Calibration Due Date
7550DT	9111100	02/01/2004

Test Date: 08/10/2005

Test Time: 03:17:56 AM

User Name:

Device Tested

Model Number: BoX C LQX2

Serial Number: I5 thru J2

Setup Filename: IN Helium

Results

	Test Type	Memory	Step	Pass/Fail	Test Result	Timer	Parameter 1	Parameter 2
1	DC Withstand	10	1	Pass	Pass	60.0s	2.50KV	0.0microamps

MQX2

Test Instruments Used

Test Model #	Test Serial #	Calibration Due Date
7550DT	9111100	02/01/2004

Test Date: 08/10/2005

Test Time: 03:20:31 AM

User Name:

Device Tested

Model Number: BoX C LQX2

Serial Number: J3 thru J6

Setup Filename: IN Helium

Results

	Test Type	Memory	Step	Pass/Fail	Test Result	Timer	Parameter 1	Parameter 2
1	DC Withstand	10	1	Pass	Pass	60.0s	2.50KV	0.0microamps

MQX2

Test Instruments Used

Test Model #	Test Serial #	Calibration Due Date
7550DT	9111100	02/01/2004

Test Date: 08/10/2005

Test Time: 03:23:27 AM

User Name:

Device Tested

Model Number: BoX C LQX2

Serial Number: K1 thru K4

Setup Filename: IN Helium

Results

	Test Type	Memory	Step	Pass/Fail	Test Result	Timer	Parameter 1	Parameter 2
1	DC Withstand	10	1	Pass	Pass	60.0s	2.50KV	0.0microamps

MQX2

Test Instruments Used

Test Model #	Test Serial #	Calibration Due Date
7550DT	9111100	02/01/2004

Test Date: 08/10/2005

Test Time: 03:26:03 AM

User Name:

Device Tested

Model Number: BoX C LQX2

Serial Number: K5 thru L2

Setup Filename: in Helium

Results

	Test Type	Memory	Step	Pass/Fail	Test Result	Timer	Parameter 1	Parameter 2
1	DC Withstand	10	1	Pass	Pass	60.0s	2.50KV	0.0microamps

MCX2

Test Instruments Used

Test Model #	Test Serial #	Calibration Due Date
7550DT	9111100	02/01/2004

Test Date: 08/10/2005

Test Time: 03:29:38 AM

User Name:

Device Tested

Model Number: BoX C LQX2

Serial Number: 32 pin connector

Setup Filename: IN itelium

Results

	Test Type	Memory	Step	Pass/Fail	Test Result	Timer	Parameter 1	Parameter 2
1	DC Withstand	9	3	Pass	Pass	60.0s	0.30KV	0.0microamps